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# Understanding the dopant induced effects on SFX-MeOTAD for perovskite solar cells: a spectroscopic and computational investigation†

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SFX-MeOTAD [2,2',7,7'-tetrakis(*N,N*-di(4-methoxyphenyl)amino)-spiro-(fluorene-9,9'-xanthene)] (also known as X60) has emerged as a cost-effective alternative to the ubiquitous, but excessively-expensive, spiro-MeOTAD hole transport material (HTM) in perovskite solar cells. Using its pre-oxidised dicationic salt, SFX-(TFSI)<sub>2</sub>, a controlled concentration dependent conductivity tuning of this HTM without the requirement of air (oxygen) exposure has been carried out. This study details the modifications in the optical and electrical properties of this low cost HTM as a function of the concentration of the dicationic salt (0–100 mol%) using UV-vis absorption and electrical conductivity measurements. X-ray absorption and photoelectron spectroscopy investigations have been carried out to elucidate the role of the dicationic salt in the enhanced electronic properties of SFX-MeOTAD. By incorporating the dicationic SFX-(TFSI)<sub>2</sub> it has been shown that the conductivity of SFX-MeOTAD increased by 4 orders of magnitude from  $2.55 \times 10^{-8} \text{ S cm}^{-1}$  to  $9.4 \times 10^{-4} \text{ S cm}^{-1}$  when using an optimal dopant concentration of 20.5 mol%. The degree of oxidation of SFX-MeOTAD was determined through UV-vis absorption and consolidated using the computational calculations. The XPS study reveals that doping SFX-MeOTAD with SFX(TFSI)<sub>2</sub> not only results in the oxidation of the HTM but also leads to a variation in the local chemistry around carbon and nitrogen which directly influences the conductivity of the doped films. NEXAFS studies indicate that doping enhances the aromatic nature of the molecule initially but increasing the dopant concentration further affects the aromaticity and possibly the  $\pi$  stacking, similar to the trend seen in dopant concentration dependent conductivity of the SFX-MeOTAD films. These findings have implications on the choice of dopant concentration and counterions more generally for triarylamine based HTMs.

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## 1. Introduction

Perovskite solar cells (PSCs) evolved from dye-sensitised solar cells (DSSCs) after Kojima *et al.* utilised a lead halide perovskite as a sensitiser in the DSSC.<sup>1</sup> Following on from this, there has been a surge of research interest in PSCs due to their extraordinary material properties *e.g.* tuneable bandgap of the absorber material, long charge carrier diffusion lengths and lifetimes and lower production costs due to easy manufacturing *via* solution processing.<sup>2,3</sup> To date, the highest power conversion efficiency (PCE) recorded for PSCs is 25.5%.<sup>4</sup> Perovskites are ambipolar in nature and hence can be used in different device architectures.<sup>5</sup> PSCs are layered devices that contain the perovskite absorber sandwiched between an n-type electron transport layer (ETL) and a p-type hole transport layer (HTL). The role of the hole transport layer is to transport the photogenerated holes, increase selectivity and reflectivity of the top contact and increase the internal quantum efficiency of the PSC.<sup>6</sup> An appropriate hole transport

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between the experimental observations and theoretical calculations.

## 2. Experimental

### 2.1 Synthesis of SFX-MeOTAD and SFX-(TFSI)<sub>2</sub>

Synthesis of SFX-MeOTAD was carried out as reported in the literature.<sup>21</sup> Synthesis of SFX-(TFSI)<sub>2</sub> was similar to that of spiro(TFSI)<sub>2</sub> as reported by Nguyen *et al.*<sup>8</sup> Briefly, SFX-MeOTAD and silver bis(trifluoromethanesulfonyl)imide were mixed in dry dichloromethane under nitrogen. The mixture was stirred for 24 hours at room temperature. The resulting mixture was then diluted with methylene chloride, filtered and the solvent was removed by rotary evaporation. The residual solid was dissolved in dichloromethane and then precipitated in dry diethyl ether twice. The resulting powder was dried under vacuum and the composition was confirmed by CHN elemental analysis (%): calculated C 56.66, H 3.80, and N 4.66. Result: C 56.50, H 3.68, and N 4.59.

### 2.2 Deposition of SFX(TFSI)<sub>2</sub> doped SFX-MeOTAD films

Different concentrations [0–100 mol%] of SFX-(TFSI)<sub>2</sub> were mixed with SFX-MeOTAD in anhydrous chlorobenzene to a combined concentration of 0.15 M. To this 0.12 M 4-*tert*-butylpyridine was added before spin coating on cleaned glass (for absorbance and conductivity measurements) or FTO coated glass (for XPS and NEXAFS measurements) at 2000 rpm for 1 minute. For conductivity measurements aluminium electrodes (~80 nm) were deposited by thermal evaporation (~10<sup>-6</sup> mbar) on doped and undoped SFX-MeOTAD thin films coated on glass.

### 2.3 Characterisation techniques

Elemental analyses of SFX-MeOTAD and SFX-(TFSI)<sub>2</sub> were carried out using a Carlo Erba CE1108 Elemental Analyser. For evaluating the conductivity of the SFX-MeOTAD films doped with varying concentrations of SFX-(TFSI)<sub>2</sub> (0–100 mol%), *I*-*V* measurements were carried out in the dark inside a N<sub>2</sub> filled glovebox *via* a two-point probe method using a Keithley 4200-SCS Parameter Analyser. For each dopant concentration an average of four *I*-*V* measurements has been recorded. The conductivity was evaluated using the inverse of the gradient of the *I*-*V* plots, the area between the electrodes and thickness of the films. The film thickness was measured in air using an atomic force microscope (AFM) (Digital Instruments, Dimension 3100) in the tapping mode (using TESPA-V2 probes and Nanoscope III software) with ten measurements per sample used to determine the average thickness. In order to handle the AFM data, WSMX software was used.<sup>25</sup> The absorbance of the SFX-MeOTAD thin film samples with different SFX(TFSI)<sub>2</sub> doping concentrations (0–100%) was studied using a UNICAM UV 300 spectrophotometer in the range of 290–1100 nm. The electronic properties of the undoped and SFX-(TFSI)<sub>2</sub> doped SFX-MeOTAD films were investigated using XPS with a load-locked KRATOS XSAM-800 instrument equipped with a dual anode X-ray source using a Mg K $\alpha$  (1253.6 eV) excitation source. For C 1s, F 1s, O 1s and N 1s core levels, the

photoelectrons were collected using a high magnification analyser more from the smallest possible area on the specimen. CasaXPS version 2.3.16 software was used for analysing the XPS data. NEXAFS experiments were performed at the beam-line 8-2 of the Stanford Synchrotron Radiation Lightsources of SLAC National Accelerator Laboratory.<sup>26</sup> The samples were vacuum sealed and packed with molecular sieves during transport to carry out XPS and NEXAFS experiments. The samples were mounted on an aluminium stick with a conductive carbon tape and measurements were performed under ultra-high vacuum conditions (<1 × 10<sup>-9</sup> Torr). The energy of the incident beam was calibrated at the carbon dip (284.7 eV) arising from the contaminations in the beamline optics. Beamline slits and the pass energy of the analyser were set to achieve a total energy resolution of 0.3 eV. To eliminate the effects of sample orientation on the intensities of the resonances, the C and N K-edge spectra were acquired in the total electron yield (TEY) mode at 54.7° (magic angle) incidence of the soft X-ray beam between 280.0 to 330.0 eV and 380.0 to 440.0 eV, respectively. The spectra were then normalised to a linear background following the protocol developed by Wang *et al.*<sup>27,28</sup> The incoming flux (*I*<sub>0</sub>) was measured using a gold mesh in the beamline and the signal was divided by the incident flux for normalisation. Pre- and post-edge normalisation were carried out from 275–285 eV and 320–330 eV for the C K-edge and the edge jump was normalised to unity. C and N K-edge NEXAFS spectra of the pristine SFX-MeOTAD and SFX-(TFSI)<sub>2</sub> doped SFX-MeOTAD films were probed individually to understand the variations in the electronic properties as a function of dopant concentration.

### 2.4 Computational details

The molecular structures of SFX-MeOTAD and its oxidised forms *i.e.* SFX-MeOTAD<sup>+</sup>, SFX-MeOTAD<sup>2+</sup> and SFX-MeOTAD<sup>4+</sup> were optimised in chlorobenzene solvent using the PBE0 functional and the 6-311G(d,p) basis set.<sup>29,30</sup> The calculations were carried out using Gaussian 16.<sup>31</sup> The solvation model used in the calculations was the default IEF-PCM solvation model.<sup>32</sup> The changes in the electronic structure and the absorption spectra, which are instigated by the oxidation from SFX-(TFSI)<sub>2</sub>, was investigated using the TDDFT calculations that also employed the PBE0 functional and the 6-311G(d,p) basis set. The solvation model used was the default IEF-PCM model in chlorobenzene. For all the species, 60 excitation states were calculated.

## 3. Results and discussion

### 3.1 Electrical and optical properties of SFX(TFSI)<sub>2</sub> doped SFX-MeOTAD

Conductivity values of the SFX-MeOTAD films doped with varying molar percentages of SFX-(TFSI)<sub>2</sub> were evaluated from the *I*-*V* measurements carried out in the dark inside a N<sub>2</sub> filled glovebox using a two-point probe method. As shown in Fig. 2(a) and (b), pristine SFX-MeOTAD has a rather low conductivity of 2.55 × 10<sup>-8</sup> S cm<sup>-1</sup> and as the molar concentration of





**Table 1** The Main optimised geometrical parameters (mean values on four quasi symmetric units) of SFX-MeOTAD (neutral) and its oxidised forms (1<sup>+</sup>, 2<sup>+</sup>, 4<sup>+</sup>)

Parameter <sup>a</sup>	Neutral ( <i>vacuo</i> )	Neutral (chlorobenzene)	1 <sup>+</sup> (chlorobenzene)	2 <sup>+</sup> (chlorobenzene)	4 <sup>+</sup> (chlorobenzene)
C <sub>1</sub> -C <sub>2</sub>	1.528	1.523	1.520	1.520	1.530
C <sub>2</sub> -C <sub>3</sub>	1.395	1.396	1.396	1.388	1.391
C <sub>2</sub> -C <sub>7</sub>	1.389	1.389	1.390	1.393	1.393
C <sub>3</sub> -C <sub>4</sub>	1.389	1.392	1.392	1.400	1.394
C <sub>4</sub> -C <sub>5</sub>	1.400	1.403	1.403	1.408	1.402
C <sub>4</sub> -N <sub>9</sub>	1.415	1.408	1.407	1.392	1.411
C <sub>5</sub> -C <sub>6</sub>	1.380	1.380	1.379	1.375	1.376
C <sub>6</sub> -C <sub>7</sub>	1.395	1.394	1.395	1.396	1.396
C <sub>7</sub> -O <sub>8</sub>	1.362	1.365	1.363	1.359	1.354
N <sub>9</sub> -C <sub>10</sub>	1.416	1.414	1.415	1.416	1.403
N <sub>9</sub> -C <sub>11</sub>	1.409	1.414	1.413	1.414	1.393
∠(C <sub>3</sub> C <sub>4</sub> N <sub>9</sub> C <sub>11</sub> )	124	142	143	148	139
∅	116	116	116	116	116

<sup>a</sup> Bond lengths are in angstroms and bond angles are in degrees.

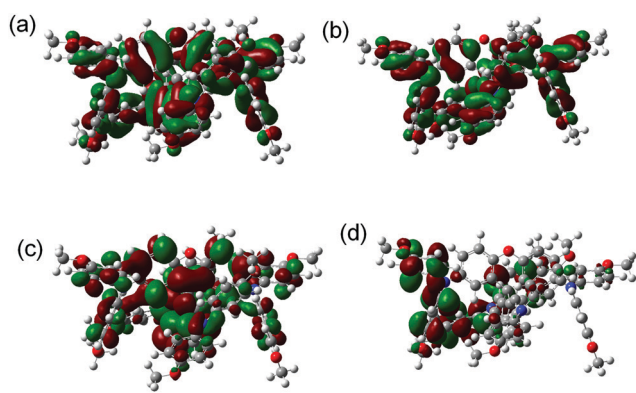
the different oxidised states in the solvent as compared to that *in vacuo*. As the level of oxidation increases, the spiro[fluorene-9,9'-xanthene] core reacts by constricting the C<sub>7</sub>-O<sub>8</sub> bond (1.365 Å in the neutral species and 1.354 Å in the +4 species). There is also the shrinking of the C<sub>1</sub>-C<sub>2</sub> from the neutral species to the +2 species but the length of the same bond increases when oxidised to +4. The C<sub>2</sub>-C<sub>7</sub> bonds lengthen from neutral to +4. It can however be seen that the C<sub>4</sub>-N<sub>9</sub> bond decreases from neutral to +2 but increases when further oxidised to +4. There is an increase in ∠ when going from the neutral to +2 but then decreases when going into the +4 state. There was no change in the OMe-phenyl angle when the oxidation state was increased.

An isosurface representation of the molecular frontier orbital of neutral SFX-MeOTAD is shown in Fig. 3 (a full table of energies can be found in the ESI;† see S2). For the neutral species there are two quasi-degenerate highest occupied molecular orbitals (HOMO/HOMO-1) that are delocalised across the fluorene core of the molecule and the triarylamine groups attached (HOMO), and also due to the contribution of the lone pairs on the O atom within the spiro[fluorene-9,9'-xanthene] core, lone pairs from the nitrogen atoms and the phenyl ligands into the top of the molecule (HOMO-1) (see Fig. 3(a)). When going down in energy to the HOMO-2 and HOMO-3 energy levels it can be seen that the

orbitals are delocalised within the phenyl ligands and the nitrogen lone pairs contributing to delocalisation (Fig. 3(b)).

The two lowest unoccupied molecular orbitals (LUMO/LUMO+1) show π\* character [Fig. 3(c)]; the delocalisation is spread across the spiro[fluorene-9,9'-xanthene] core into the phenyl ligands attached to the xanthene part of the core of the molecule and at higher energy levels, such as LUMO+10, the orbitals are localised in the outer *N*-phenyl-OMe ligands (Fig. 3(d)). The HOMO energy level was calculated to be -4.87 eV and is in good accordance with both the experimental and other computational values reported for SFX-MeOTAD (experimental value of -5.16 eV and computational values of -5.11 eV and -5.61 eV).<sup>22,24,37</sup> Deng *et al.* also calculated the HOMO of SFX-MeOTAD using different functional methods of BMK, PBE0, B3LYP, CAM-B3LYP, M06 and M06-2X, all using the 6-31G(d) basis set. In their study, the BMK method was explored in detail as it was found to give a value close to that measured experimentally; however, the method led to an energy gap of 4.87 eV (largest reported for SFX-MeOTAD). B3LYP and M06-2X gave values for the HOMO for SFX-MeOTAD at -4.55 eV and -5.87 eV.<sup>38</sup> The LUMO ranged from -0.28 eV to -1.05 eV using the different functional methods mentioned above.<sup>38</sup> Additionally, there have been reports with the LUMO determined to be 0.48 eV, -1.15 eV and -2.56 eV.<sup>22,24,37</sup> The HOMO-LUMO gap was calculated to be 3.85 eV computationally and using the absorbance onset for pristine SFX-MeOTAD from Fig. 2(c) the experimental HOMO-LUMO gap was calculated to be 2.96 eV. The HOMO-LUMO gaps of SFX-MeOTAD have been determined experimentally in other studies to be 2.96 eV and 3.05 eV<sup>21,22</sup> and computationally the energy gaps have been calculated to be 3.10 eV and 5.45 eV.<sup>37,38</sup>

When oxidised to the +1 *i.e.* SFX-MeOTAD<sup>+</sup> species, a doublet ground state is formed and the orbitals within this are split into α and β manifolds that have different spatial wave functions and so this results in different energies for each manifold as seen in Fig. 4. The HOMO in the α manifold is stabilised by 0.74 eV with respect to its β manifold counterpart and is almost degenerate and corresponds to the HOMO-1 of the neutral species. It can be seen that the HOMO and LUMO



**Fig. 3** Isodensity plot showing the frontier orbitals of neutral SFX-MeOTAD (a) HOMO/HOMO-1, (b) HOMO-2/HOMO-3, (c) LUMO/LUMO+1, and (d) LUMO+10.





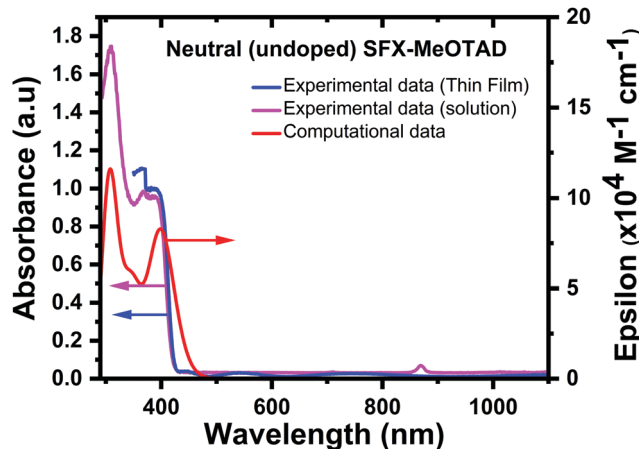


Fig. 5 Comparison of experimental [thin film (blue) and solution (magenta)] and computational absorption spectra (red) for neutral (undoped) SFX-MeOTAD.

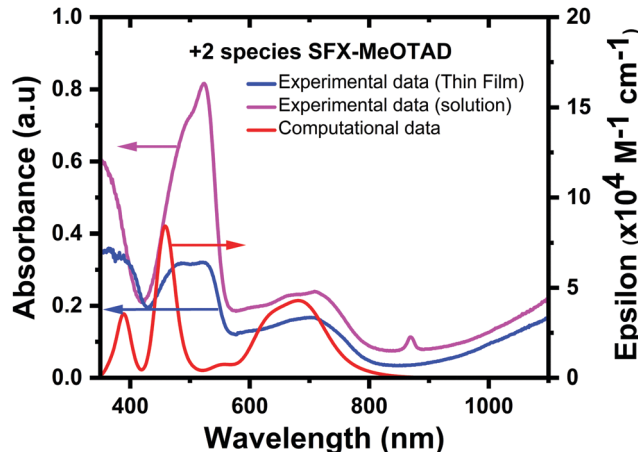


Fig. 6 Comparison of experimental [thin film (blue) and solution (magenta)] and computational absorption spectra (red) for SFX-MeOTAD<sup>2+</sup>.

700–800 nm was observed in the measured absorbance curve of the SFX-MeOTAD film without any added SFX(TFSI)<sub>2</sub> (blue curve in Fig. 5), which is associated with photo-doping in the presence of oxygen that might have occurred during transferring the samples from the glovebox to the UV-vis spectrophotometer. In the solution samples, a small peak is observed at *ca.* 890 nm for all solution samples, but this is possibly due to debris interfering with the beam inside the spectrophotometer.

From the calculated TD-DFT eigenvalues the transitions that are involved in the band centred at 400 nm are from the HOMO to the LUMO and show strong local excitation character and also correspond to  $\pi$ - $\pi^*$  transitions. Whereas the transitions from the HOMO/HOMO-1 to the LUMO+11 and LUMO+8 result in a peak at 308 nm with a predominant charge transfer (CT) character but also some local excitation character at one of the triarylamine groups bonded to the xanthene part of the core and both triarylamine groups attached to the fluorene part of the core. This peak was found to be more intense than that found at 400 nm (see S4, ESI<sup>†</sup> for all MO isodensity plots of transitions mentioned).

In addition to this, the experimental and calculated spectra of the +2 species were compared and benchmarked with each other. The spectrum of the pristine SFX-(TFSI)<sub>2</sub> dicationic salt is shown in Fig. 6. Computationally it was shown the peaks that correspond to this species appear at 389 nm, 459 nm and 681 nm. From analysing the TD-DFT eigenvalues, it can be inferred that the transition from low-lying HOMO orbitals HOMO-13 to the LUMO+1 in the  $\beta$  manifold corresponds to the 459 nm peak. Transitions in the  $\alpha$  manifold, HOMO-1 to the LUMO also corresponds to the band at 459 nm, whereas the transitions from the HOMO-7/HOMO-5 orbitals to the LUMO/LUMO+1 correspond to the band at 681 nm in the  $\beta$  manifold. These transitions show  $\pi$ - $\pi^*$  character and predominantly local excitation character but there is some partial CT character. Further analysis of the eigenvalues shows that a transition from the HOMO $\alpha$  to the LUMO+3 $\alpha$  corresponds to the peak at 389 nm with a mixture of local excitation and CT character.

When comparing this to the experimental data, which show an absorbance peak at 386 nm, there is a very good correlation between the experimental and computational values. The experimental spectrum shows peaks at 520 nm and 703 nm, which again provides good agreement between the calculated (blue shifted by 0.3 eV for peaks found at *ca.* 500 nm and <0.1 eV for the peaks at *ca.* 700 nm) and experimental thin film bands. When measured in solution, the absorbance bands were measured as *ca.* 350 nm, 524 nm and 709 nm (0.35 eV blue shifted, 0.33 eV red shifted, and 0.07 eV red shifted compared to the computational results, respectively). In all cases, the difference between the calculated and experimental bands is within the limits of accuracy of the TD-DFT approach for the PBE0 method ( $\Delta E = \pm 0.2$ –0.3 eV for singlet excitations and up to 0.5 eV for triplet excitations).<sup>39</sup> The intensities of the calculated bands after 400 nm (red line, Fig. 6) are the same as the experimental UV bands (blue line, Fig. 6). An opposite behaviour was observed in the simulated absorption spectrum of spiro-MeOTAD as compared to the experimentally obtained UV-vis absorbance.<sup>40</sup> As shown by Zhang *et al.*, the +2 oxidation state of spiro-MeOTAD can absorb around 2000 nm.<sup>36</sup> This behaviour was also observed in the SFX-MeOTAD<sup>2+</sup> calculations, where a peak was observed at 1937 nm and corresponds to the transitions between the HOMO-1 $\beta$  orbital and the LUMO+1 $\beta$  orbital (see S5, ESI<sup>†</sup> for visualised MO transitions for SFX-MeOTAD<sup>2+</sup>). This band was not able to be measured experimentally due to the limitations of the equipment.<sup>39</sup>

When doping SFX-MeOTAD with the dicationic salt of SFX-MeOTAD the following mechanism is assumed to take place, in analogy to spiro-MeOTAD:<sup>35</sup>



Therefore, TD-DFT calculations were conducted on the mono-cation of SFX-MeOTAD and the calculated absorption spectrum showed peaks at 454 nm and 611 nm, see Fig. 7. There is also a peak at 360 nm thus showing that there has been a blue shift in the absorbance bands as compared to the neutral species.



The band at a wavelength of 454 nm corresponds to the transitions that occur in the  $\alpha$  manifold orbitals from the HOMO orbitals, the HOMO– $2\alpha$  orbital to the LUMO $\alpha$ , whereas the band at 611 nm corresponds to the transitions occurring at the low-lying HOMO– $7\beta$ /HOMO– $8\beta$  to the LUMO $\beta$  orbital. These show that the local excitation character in one of the triarylamine groups in the fluorene portion of the core but there is also some partial CT character as well. When compared to the experimental results from Fig. 2(c), the bands are present at *ca.* 520 nm and *ca.* 680 nm, the values obtained through the computational methods are in agreement with the experimental values and fall into the limits of accuracy expected from using the PBE0 method.<sup>39</sup> When comparing the intensities of the computed spectra it can be seen that the intensity of the absorption bands at *ca.* 450 nm and *ca.* 680 nm is much higher for the +2 species than the +1 species (see S6, ESI† for visualised MO transitions for SFX-MeOTAD<sup>+</sup>).

From the above experimental and calculated data and using the equation for oxidising SFX-MeOTAD with a dicationic salt we can extrapolate that as we increase the concentration of the dicationic salt, for concentrations that are below 50% dopant, all the SFX-(TFSI)<sub>2</sub> is utilised to convert the neutral SFX-MeOTAD to the monocation so this gives rise to an increase in the intensity of the peak found at *ca.* 522 nm. At concentrations over 50%, there is an excess of the dication; therefore, this describes the increase in the band *ca.* 680 nm. This means that for the optimal dopant concentration of 20.5%, all of the dicationic salt is used to convert the neutral SFX-MeOTAD to the SFX-MeOTAD monocation. Using the redox potentials known for SFX-MeOTAD, the doping efficiency of the optimal dopant mol% can be found.<sup>21</sup> Combining neutral SFX-MeOTAD and the dicationic salt would result in a compositional mixture containing the neutral, monocation and dication species at equilibrium. The equilibrium constant of the redox reaction was calculated using the Nernst equation and thus the contribution of each species can be calculated. See S10 in the ESI† for the full calculation. From the calculation, a solution that initially

contained neutral SFX-MeOTAD and 20.5 mol% SFX-(TFSI)<sub>2</sub> should have almost no dication species at equilibrium. The final concentrations of the individual species in this optimal dopant mol% are 59.08%, 40.84% and 0.08% for neutral, monocation and dication, respectively. Taking this into account we were able to create a computational absorption spectrum, using the oscillator strengths and their corresponding wavelengths, for the 20.5% doped sample (redline, Fig. 8). See S7–S9 in the ESI† for a full list of oscillator strengths and the corresponding orbital contributions. The calculated maximum absorption bands were found to be 389 nm, 459 nm and 681 nm. When compared to the experimental data (thin film (blue) and solution (magenta), Fig. 8), these values are in excellent agreement as the difference between the calculated and experimental bands are within the limits of accuracy of the TD-DFT approach (band 1  $\Delta E = \pm 0.16$  eV (solution),  $\Delta E = \pm 0$  eV (thin film); band 2  $\Delta E = \pm 0.32$  eV (solution),  $\Delta E = \pm 0.32$  eV (thin film) and band 3  $\Delta E = \pm 0.07$  eV (solution),  $\Delta E = \pm 0.05$  eV (thin film)).<sup>39</sup> As mentioned above, a simplistic picture proposed earlier for spiro-MeOTAD was assumed to be true for SFX-MeOTAD as well, where it is assumed that all the dicationic salt is used to convert SFX-MeOTAD into its monocation. However, conversion of SFX-MeOTAD<sup>2+</sup> to SFX-MeOTAD<sup>4+</sup>, as proposed by Zhang *et al.*,<sup>36</sup> cannot be ruled out. DFT and TD-DFT computational calculations were also carried out for the +4 triplet, and the absorbance maxima were found at *ca.* 630 nm and *ca.* 760 nm. These peaks were not seen in the experimental data of the doped samples [Fig. 2(c)]; therefore, we can assume that +4 SFX-MeOTAD is not present in the measured films.

### 3.2 Electronic properties of SFX(TFSI)<sub>2</sub> doped SFX-MeOTAD

X-Ray photoelectron spectroscopy (XPS) is a highly surface-sensitive, element-specific technique which is used to probe the variation in local chemistry around the carbon, nitrogen and oxygen atoms as a result of the nearest-neighbour interaction during the doping of SFX-MeOTAD with different concentrations of SFX(TFSI)<sub>2</sub>. High resolution core level XPS spectra were acquired and deconvoluted to understand the

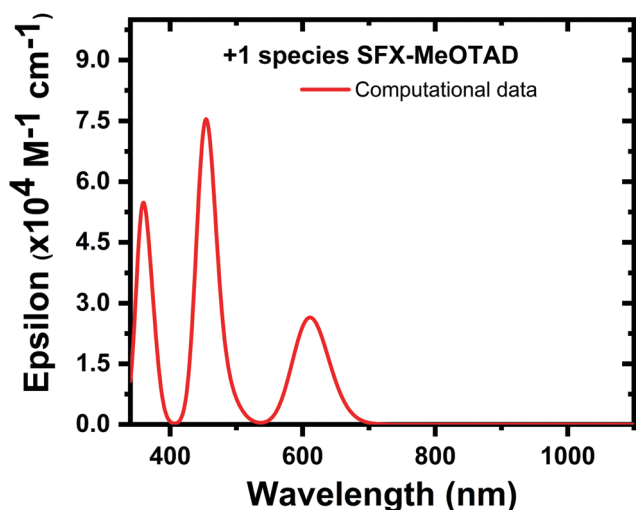


Fig. 7 Computational absorption spectrum for SFX-MeOTAD<sup>+</sup>.

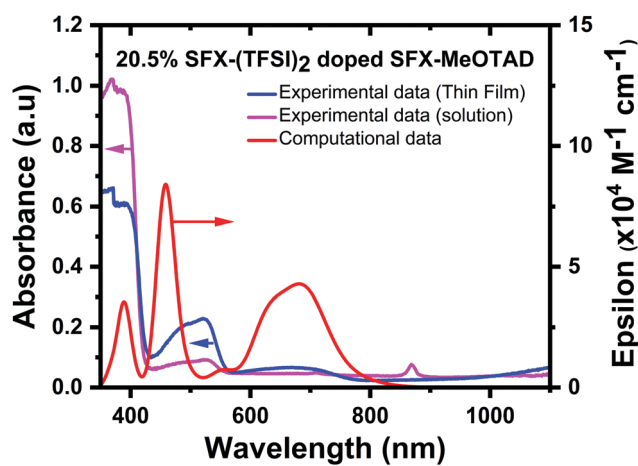


Fig. 8 Comparison of experimental [thin film (blue) and solution (magenta)] and computational absorption spectra (red) for 20.5% SFX-(TFSI)<sub>2</sub> doped SFX-MeOTAD.









with HTM containing  $\text{Na}^+$  counterion were around 50% less efficient than devices made using HTM with  $\text{CH}_3\text{NH}_3^+$  counterion.<sup>67</sup> An improvement in hole conductivity and homogeneity was observed in an ionic type HTM containing TFSI<sup>-</sup> counterions as compared to the same HTM that did not contain the counterions.<sup>68</sup> Counterions used in ionic liquids such as  $\text{PF}_6^-$ ,  $\text{CF}_3\text{SO}_3^-$  and  $\text{BF}_4^-$  are also found in conducting polymers used for photovoltaic applications because the counterions are weakly interacting due to a shielded charge.<sup>69</sup> A halide counterion ( $\text{Br}^-$ ) in the A–D–A type ionic molecule as HTM was compared with the same HTM with TFSI<sup>-</sup> counterions. It was found that HTMs with the TFSI<sup>-</sup> counterions showed better performance in PSCs than those with  $\text{Br}^-$  as the counterion. Although devices made with the TFSI<sup>-</sup> containing HTM exhibited higher efficiencies, the performance of devices using HTM with  $\text{Br}^-$  counterions was still better than that of devices where the HTM did not contain any counterions. This is because the HOMO is located at a deeper energy level due to the high electron withdrawing effect of the quarternarised part of the HTM that helps to modify the HOMO.<sup>70</sup>

From the results obtained in the present study the optimal doping concentration is 20.5% as this is where the conductivity values started to plateau. It is important to note that the doping affects not only conductivity but also other properties like hydrophobicity, energy levels, film processing ability *etc.*, and hence the best performing devices might not always correspond to optimal doping. Upon using spiro-(TFSI)<sub>2</sub> as the dopant, a downshift in the ionisation potential of spiro-OMeTAD was observed. The best performing device was shown with 14 mol% spiro-(TFSI)<sub>2</sub>. At an optimal dopant concentration, the hydrophobicity of the film was shown to increase as the contact angle increases from 72.2° for the Li-TFSI doped spiro-OMeTAD to 83.3° for the spiro-OMeTAD with optimal spiro-(TFSI)<sub>2</sub> doping. Cross-sectional SEM imaging showed that voids appeared in the Li-TFSI doped spiro-OMeTAD devices after aging for 300 hours at 50 °C but this was not observed in the optimal spiro-(TFSI)<sub>2</sub> devices. These observations showed that the spiro-(TFSI)<sub>2</sub> doped films have a greater stability in high moisture and oxygen environments.<sup>35</sup> When (MeO-TPC)TFSI was used as the dopant, the conductivity of spiro-OMeTAD increased drastically at 50% dopant but the best performing device was made with 30% dopant with an efficiency of 17.9%. The contact angle also increased showing that the film hydrophobicity increased. The film morphology showed that there were no visible cracks or aggregation of the film unlike the film made with FK209.<sup>71</sup> Using acid additives to help in enhancing the conductivity of spiro-OMeTAD was observed to decrease the ionisation energy of the HTM and also the Fermi level. There was no noticeable change in the ionisation energy and Fermi level between spiro-OMeTAD doped with LiTFSI and cobalt(III) complexes and those that had the acid additives. It was concluded that the increase in conductivity was due to hydrogen-bonding that increases the delocalisation of electrons.<sup>12</sup>

NEXAFS studies have also been carried around the N K-edge to understand the effect of SFX(TFSI)<sub>2</sub> doping on SFX-MeOTAD. The positions and assignments of the N K-edge resonances of pristine and doped samples are summarised in Table S13 in the

ESI.† N K-edge NEXAFS spectra of samples analysed are shown in Fig. 11 and are dominated by four resonances at 401.1, 402.7, 405.1 and 407.7 eV. Splitting of the N 1s →  $\pi^*$  resonance in the 10%, 20% and 100% samples may be attributed to the difference in bond length between the N–C molecules as has been previously observed for spiro-MeOTAD<sup>40</sup> and SFX-MeOTAD in this study. A modest difference in C–N bond length in the case of spiro(TFSI)<sub>2</sub> has been reported<sup>36</sup> and a similar variation in bond length in the case of SFX(TFSI)<sub>2</sub> has been observed in this study [Table 1]. This trend would corroborate the fact that the presence of electron-donating methoxy groups affects the charge density of the molecules and plays a crucial role in influencing the charge transfer process. The resonance at 402.9 eV can be attributed to the transitions to the antibonding orbitals localised on amine moieties.<sup>72</sup> An increase in the area under the curve from the pristine 0% to 10% and 20% doped samples signifies an enhancement in the nitrogen content of the molecules as the edge-jump intensity is proportional to the total nitrogen content in the molecules. SFX(TFSI)<sub>2</sub> can have multiple nitrogen environments stemming from the different oxidation potentials on the amine N in the two halves of SFX-MeOTAD and the nitrogen from the dopant. The substantial enhancement in the nitrogen content of doped molecules point towards an increase in the  $\pi^*$  and  $\sigma^*$  density of states (DOS) over nitrogen and may also indicate the presence of additional decay channels available to the 10% and 20% doped samples *via* the formation of a charge transfer complex similar in lines to the spiro-MeOTAD<sup>+</sup>TFSI<sup>-</sup> which creates additional DOS over N through the  $(\text{CF}_3\text{SO}_2)_2\text{N}^-$  counteranion in spiro(TFSI)<sub>2</sub>. Pristine 0% sample has the lowest area under the curve due to the lower nitrogen environment available compared to the 10%, 20% and 100% samples. Interestingly, increasing the dopant concentration beyond 10% shows a decrease in the area under the curve which can probably be associated with the localisation of charge density due to enhanced TFSI concentration and can be corroborated

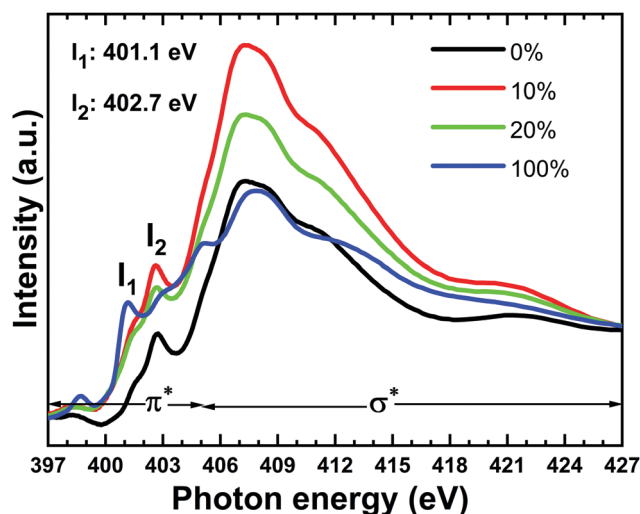


Fig. 11 Comparison of N K-edge NEXAFS spectra corresponding to SFX-MeOTAD [0%], SFX-MeOTAD doped with 10% SFX(TFSI)<sub>2</sub> [10%], SFX-MeOTAD doped with 20% SFX-(TFSI)<sub>2</sub> [20%] and SFX(TFSI)<sub>2</sub> dopant [100%].



with the C K-edge spectra where the aromaticity is found to decrease upon using a dopant concentration beyond 10% (Fig. 10).

Thus, it can be concluded that doping SFX-MeOTAD with SFX(TFSI)<sub>2</sub> results in an enhancement in the aromatic nature which might possibly suggest improved  $\pi$  stacking between the molecules until an optimal concentration is reached, at which point a decrease is observed.

## 4. Conclusion

This study presents a detailed investigation of the modifications in the molecular structure and the electronic and optical properties of SFX-MeOTAD by doping it with its pre-oxidised form *viz.*, a dicationic salt SFX(TFSI)<sub>2</sub>, probed using XPS, NEXAFS and detailed DFT, and TD-DFT computational calculations. By varying the doping concentration of the dicationic salt over a larger range [0–100%], it was possible to find the optimal doping concentration which resulted in four orders of increase in the conductivity of the pristine SFX-MeOTAD. An optimal doping concentration of 20.5% SFX-(TFSI)<sub>2</sub> resulted in films with a conductivity of  $9.43 \times 10^{-4} \text{ S cm}^{-1}$ . Computational calculations provided detailed understanding of the geometric structure and the electronic and optical properties of SFX-MeOTAD and its oxidised forms. This allowed us to computationally calculate the absorbance spectrum for SFX-MeOTAD doped with the optimal dopant concentration of 20.5% SFX-(TFSI)<sub>2</sub>. XPS data reveals that doping with SFX(TFSI)<sub>2</sub> results not only in the oxidation of SFX-MeOTAD but also in variations of the local chemistry around carbon and nitrogen which would influence the conductivity of the doped films, indicating that the counterion of the dopant can strongly interact with the oxidised HTM molecules and affect conductivity. Doping SFX-MeOTAD with SFX(TFSI)<sub>2</sub> helps in enhancing the aromatic nature of the molecule initially but increasing the dopant concentration further affects the aromaticity and possibly the  $\pi$  stacking. The conductivity values of the doped samples follow a similar trend. Based on the results of the present study, the following considerations are important for doping triarylamine based HTM for perovskite solar cells (a) proper choice of the counterion in the dopant as it interacts strongly with the HTM; (b) although the HTM may contain multiple triarylamines, each molecule is likely to be not more than singly charged at the optimal dopant concentration; and (c) optimising the dopant concentration will strongly affect the conductivity.

## Conflicts of interest

There are no conflicts to declare.

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using the ARCHIE-WeSt High-Performance Computer ([www.archie-west.ac.uk](http://www.archie-west.ac.uk)) based at the University of Strathclyde. S. K. acknowledges Royal Society IES\R2\170272 and Royal Academy of Engineering Newton fund for the funding support. M. R. M. and N. R. acknowledge the European Union's Horizon 2020 Research and Innovation Programme H2020-MSCA-IF-2014-659237 and the EPSRC Supersolar Hub for financial support.

## References

- 1 A. Kojima, K. Teshima, Y. Shirai and T. Miyasaka, *J. Am. Chem. Soc.*, 2009, **131**, 6050–6051.
- 2 G. Xing, N. Mathews, S. S. Lim, Y. M. Lam, S. Mhaisalkar and T. C. Sum, *Science*, 2013, **342**(6156), 344–347, DOI: 10.1126/science.1243167.
- 3 G. Hodes, *Science*, 2013, **342**(6156), 317–318, DOI: 10.1126/science.1245473.
- 4 NREL, Best Research-Cell Efficiency Chart|Photovoltaic Research|NREL, <https://www.nrel.gov/pv/assets/pdfs/best-research-cell-efficiencies.20200104.pdf>.
- 5 M. Liu, M. B. Johnston and H. J. Snaith, *Nature*, 2013, **501**, 395–398, DOI: 10.1038/nature12509.
- 6 W. Tress, N. Marinova, O. Inganäs, M. K. Nazeeruddin, S. M. Zakeeruddin and M. Graetzel, in *2014 IEEE 40th Photovoltaic Specialist Conference, PVSC 2014*, 2014, pp. 1563–1566.
- 7 T. Liu, K. Chen, Q. Hu, R. Zhu and Q. Gong, *Adv. Energy Mater.*, 2016, **6**, 1–17.
- 8 W. H. Nguyen, C. D. Bailie, E. L. Unger and M. D. McGehee, *J. Am. Chem. Soc.*, 2014, **136**, 10996–11001.
- 9 H. J. Snaith and M. Grätzel, *Appl. Phys. Lett.*, 2006, **89**, 262114, DOI: 10.1063/1.2424552.
- 10 J. Burschka, A. Dualeh, F. Kessler, E. Baranoff, N.-L. L. Cevey-Ha, C. Yi, M. K. Nazeeruddin and M. Grätzel, *J. Am. Chem. Soc.*, 2011, **133**, 18042–18045.
- 11 J. Burschka, F. Kessler, M. K. Nazeeruddin and M. Grätzel, *Chem. Mater.*, 2013, **25**, 2986–2990.
- 12 Z. Li, J. Tinkham, P. Schulz, M. Yang, D. H. Kim, J. Berry, A. Sellinger and K. Zhu, *Adv. Energy Mater.*, 2017, **7**, 1–8.
- 13 Q. Liu, L. Fan, Q. Zhang, A. Zhou, B. Wang, H. Bai, Q. Tian, B. Fan and T. Zhang, *ChemSusChem*, 2017, **10**, 3098–3104.
- 14 C. Chen, W. Zhang, J. Cong, M. Cheng, B. Zhang, H. Chen, P. Liu, R. Li, M. Safdari, L. Kloo and L. Sun, *ACS Energy Lett.*, 2017, **2**, 497–503.
- 15 A. Pellaroque, N. K. Noel, S. N. Habisreutinger, Y. Zhang, S. Barlow, S. R. Marder and H. J. Snaith, *ACS Energy Lett.*, 2017, **2**, 2044–2050.
- 16 A. Abate, T. Leijtens, S. Pathak, J. Teuscher, R. Avolio, M. E. Errico, J. Kirkpatrick, J. M. Ball, P. Docampo, I. McPherson and H. J. Snaith, *Phys. Chem. Chem. Phys.*, 2013, **15**, 2572.
- 17 U. B. Cappel, T. Daeneke and U. Bach, *Nano Lett.*, 2012, **12**, 4925–4931.
- 18 Z. Hawash, L. K. Ono, S. R. Raga, M. V. Lee and Y. Qi, *Chem. Mater.*, 2015, **27**, 562–569.



- 19 L. K. Ono, S. R. Raga, M. Remeika, A. J. Winchester, A. Gabe and Y. Qi, *J. Mater. Chem. A*, 2015, **3**, 15451–15456.
- 20 A. T. Murray, J. M. Frost, C. H. Hendon, C. D. Molloy, D. R. Carbery and A. Walsh, *Chem. Commun.*, 2015, **51**, 8935–8938.
- 21 M. Maciejczyk, A. Ivaturi and N. Robertson, *J. Mater. Chem. A*, 2016, **4**, 4855–4863.
- 22 B. Xu, D. Bi, Y. Hua, P. Liu, M. Cheng, M. Grätzel, L. Kloo, A. Hagfeldt and L. Sun, *Energy Environ. Sci.*, 2016, **9**, 873–877.
- 23 K. Liu, Y. Yao, J. Wang, L. Zhu, M. Sun, B. Ren, L. Xie, Y. Luo, Q. Meng and X. Zhan, *Mater. Chem. Front.*, 2017, **1**, 100–110.
- 24 J. Qu, X. Jiang, Z. Yu, J. Lai, Y. Zhao, M. Hu, X. Yang and L. Sun, *Sci. China: Chem.*, 2018, **61**, 172–179.
- 25 I. Horcas, R. Fernández, J. M. Gómez-Rodríguez, J. Colchero, J. Gómez-Herrero and A. M. Baro, *Rev. Sci. Instrum.*, 2007, **78**, 013705, DOI: 10.1063/1.2432410.
- 26 K. G. Tirsell and V. P. Karpenko, *Nucl. Instrum. Methods Phys. Res., Sect. A*, 1990, **291**, 511–517, DOI: 10.1016/0168-9002(90)90113-K.
- 27 H. Wang, C. Y. Ralston, D. S. Patil, R. M. Jones, W. Gu, M. Verhagen, M. Adams, P. Ge, C. Riordan, C. A. Marganian, P. Mascharak, J. Kovacs, C. G. Miller, T. J. Collins, S. Brooker, P. D. Croucher, K. Wang, E. I. Stiefel and S. P. Cramer, *J. Am. Chem. Soc.*, 2000, **122**, 10544–10552, DOI: 10.1021/ja000945g.
- 28 H. Wang, P. Ge, C. G. Riordan, S. Brooker, C. G. Woome, T. Collins, C. A. Melendres, O. Graudejus, N. Bartlett, S. P. Cramer, C. G. Woome, T. Collins, C. A. Melendres, X. O. Graudejus, O. N. Bartlett and S. P. Cramer, *J. Phys. Chem. B*, 1998, **102**, 8343–8346.
- 29 C. Adamo and V. Barone, *J. Chem. Phys.*, 1999, **110**, 6158–6170.
- 30 M. J. Frisch, J. A. Pople and J. S. Binkley, *J. Chem. Phys.*, 1984, **80**, 3265–3269.
- 31 M. J. Frisch, G. W. Trucks, H. E. Schlegel, G. E. Scuseria, M. A. Robb, J. R. Cheeseman, G. Scalmani, V. Barone, G. A. Petersson, O. Farkas, J. B. Foresman and J. D. Fox, Gaussian, Inc., Wallingford CT, 2016.
- 32 S. Miertuš, E. Scrocco and J. Tomasi, *Chem. Phys.*, 1981, **55**, 117–129.
- 33 R. S. Sanchez and E. Mas-Marza, *Sol. Energy Mater. Sol. Cells*, 2016, **158**, 189–194.
- 34 C. T. Weisspfennig, M. M. Lee, J. Teuscher, P. Docampo, S. D. Stranks, H. J. Joyce, H. Bergmann, I. Bruder, D. V. Kondratuk, M. B. Johnston, H. J. Snaith and L. M. Herz, *J. Phys. Chem. C*, 2013, **117**, 19850–19858.
- 35 B. Tan, S. R. Raga, A. S. R. Chesman, S. O. Fürer, F. Zheng, D. P. McMeekin, L. Jiang, W. Mao, X. Lin, X. Wen, J. Lu, Y. B. Cheng and U. Bach, *Adv. Energy Mater.*, 2019, **9**, 1–10.
- 36 W. Zhang, L. Wang, Y. Guo, B. Zhang, V. Leandri, B. Xu, Z. Li, J. M. Gardner, L. Sun and L. Kloo, *Chem. Commun.*, 2020, **56**, 1589–1592.
- 37 Z. Z. Sun, Y. L. Xu, R. Zhu and H. Y. Liu, *Org. Electron.*, 2018, **63**, 86–92.
- 38 J. Deng, W. Hu, W. Shen, M. Li and R. He, *Phys. Chem. Chem. Phys.*, 2019, **21**, 1235–1241.
- 39 D. Jacquemin, B. Mennucci and C. Adamo, *Phys. Chem. Chem. Phys.*, 2011, **13**, 16987–16998.
- 40 S. Fantacci, F. De Angelis, M. K. Nazeeruddin and M. Grätzel, *J. Phys. Chem. C*, 2011, **115**, 23126–23133.
- 41 W. Huang and S. Ptasinska, *Appl. Surf. Sci.*, 2016, **367**, 160–166.
- 42 R. Schoelin, M. H. Karlsson, S. K. Eriksson, H. Siegbahn, E. M. J. Johansson and H. Rensmo, *J. Phys. Chem. C*, 2012, **116**, 26300–26305.
- 43 J. A. Horsley, J. Stöhr, A. P. Hitchcock, D. C. Newbury, A. L. Johnson and F. Sette, *J. Chem. Phys.*, 1985, **83**, 6099.
- 44 J. L. Solomon, R. J. Madix and J. Stohr, *Surf. Sci.*, 1991, **255**, 12–30.
- 45 M. P. Keane, A. N. de Brito, N. Correia, S. Svensson and S. Lunell, *Chem. Phys.*, 1991, **155**, 379–387.
- 46 A. Baiardi, M. Mendolicchio, V. Barone, G. Fronzoni, G. A. Cardenas Jimenez, M. Stener, C. Grazioli, M. De Simone and M. Coreno, *J. Chem. Phys.*, 2015, **143**(20), 204102, DOI: 10.1063/1.4935715.
- 47 R. P. Gandhiraman, D. Nordlund, C. Javier, J. E. Koehne, B. Chen and M. Meyyappan, *J. Phys. Chem. C*, 2014, **118**, 18706–18712.
- 48 A. Ganguly, S. Sharma, P. Papakonstantinou and J. Hamilton, *J. Phys. Chem.*, 2011, **115**, 17009–17019.
- 49 J. Lehmann, D. Solomon, J. Brandes, H. Fleckenstein, C. Jacobsen and J. Thieme, *Biophysico-Chemical Processes Involving Natural Nonliving Organic Matter in Environmental Systems*, 2009, pp. 729–781.
- 50 Y. Zubavichus, A. Shaporenko, M. Grunze and M. Zharnikov, *J. Phys. Chem. A*, 2005, **109**, 6998–7000.
- 51 E. Apen, A. P. Hitchcock and J. L. Gland, *J. Phys. Chem.*, 1993, **97**, 6859–6866.
- 52 R. V. Dennis, B. J. Schultz, C. Jaye, X. Wang, D. A. Fischer, A. N. Cartwright and S. Banerjee, *J. Vac. Sci. Technol., B*, 2013, **31**, 041204.
- 53 N. Graf, E. Yegen, T. Gross, A. Lippitz, W. Weigel, S. Krakert, A. Terfort and W. E. S. Unger, *Surf. Sci.*, 2009, **603**, 2849–2860.
- 54 M. Nyberg, J. Hasselström, O. Karis, N. Wassdahl, M. Weinelt, A. Nilsson and L. G. M. Pettersson, *J. Chem. Phys.*, 2000, **112**, 5420–5427.
- 55 C. Dri, G. Fronzoni, G. Balducci, S. Furlan, M. Stener, Z. Feng, G. Comelli, C. Castellarin-Cudia, D. Cvetko, G. Kladnik, A. Verdini, L. Floreano and A. Cossaro, *J. Phys. Chem. C*, 2016, **120**, 6104–6115.
- 56 Y. Luo, M. Bernien, A. Krüger, C. F. Hermanns, J. Miguel, Y. M. Chang, S. Jaekel, W. Kuch and R. Haag, *Langmuir*, 2012, **28**, 358–366.
- 57 U. Oran, S. Swaraj, A. Lippitz and W. E. S. Unger, *Plasma Processes Polym.*, 2006, **3**, 288–298.
- 58 K. H. Hwang, W. H. E. Schwarz, T. C. Chang and U. Seeger, *Chem. Phys.*, 1987, **117**, 73–89.
- 59 J. W. Chiou, S. C. Ray, S. I. Peng, C. H. Chuang, B. Y. Wang, H. M. Tsai, C. W. Pao, H. Lin, Y. C. Shao, Y. F. Wang,



- S. C. Chen, W. F. Pong, Y. C. Yeh, C. W. Chen, L. Chen, K. Chen, M. Tsai, A. Kumar, A. Ganguly, P. Papakonstantinou, H. Yamane, N. Kosugi, T. Regier, L. Liu and T. K. Sham, *J. Phys. Chem. C*, 2012, **116**, 16251–16258.
- 60 S. C. Ray, H. M. Tsai, J. W. Chiou, B. Bose, J. C. Jan, K. Kumar, W. F. Pong, D. Dasgupta and M.-H. Tsai, *J. Phys.: Condens. Matter*, 2004, **16**, 5713–5719.
- 61 E. Yegen, A. Lippitz, D. Treu and W. E. S. Unger, *Surf. Interface Anal.*, 2008, **40**, 176–179.
- 62 D. Solomon, J. Lehmann, J. Kinyangi, B. Liang, K. Heymann, L. Dathe, K. Hanley, S. Wirick and C. Jacobsen, *Soil Sci. Soc. Am. J.*, 2008, **73**, 1817–1830.
- 63 A. V. Syugaev and A. N. Maratkanova, *J. Electron Spectrosc. Relat. Phenom.*, 2014, **195**, 71–77.
- 64 T. Ohta, K. Seki, T. Yokoyama, I. Morisada and K. Edamatsu, *Physica*, 1990, **41**, 150–153.
- 65 K. Heymann, J. Lehmann, D. Solomon, M. W. I. Schmidt and T. Regier, *Org. Geochem.*, 2011, **42**, 1055–1064.
- 66 H. Agren, V. Carravetta, L. G. M. Pettersson and O. Vahtras, *Phys. Rev. B: Condens. Matter Mater. Phys.*, 1995, **51**, 848–855.
- 67 X. Li, Y. C. Wang, L. Zhu, W. Zhang, H. Q. Wang and J. Fang, *ACS Appl. Mater. Interfaces*, 2017, **9**, 31357–31361.
- 68 J. Zhang, B. Xu, L. Yang, A. Mingorance, C. Ruan, Y. Hua, L. Wang, N. Vlachopoulos, M. Lira-Cantú, G. Boschloo, A. Hagfeldt, L. Sun and E. M. J. Johansson, *Adv. Energy Mater.*, 2017, **7**, 1–8.
- 69 M. Armand, F. Endres, D. R. MacFarlane, H. Ohno and B. Scrosati, *Nat. Mater.*, 2009, **8**, 621–629.
- 70 M. Cheng, K. Aitola, C. Chen, F. Zhang, P. Liu, K. Sveinbjörnsson, Y. Hua, L. Kloo, G. Boschloo and L. Sun, *Nano Energy*, 2016, **30**, 387–397.
- 71 W. Zhang, F. Zhang, B. Xu, Y. Li, L. Wang, B. Zhang, Y. Guo, J. M. Gardner, L. Sun and L. Kloo, *ACS Appl. Mater. Interfaces*, 2020, **12**, 33751–33758.
- 72 B. J. Schultz, R. V. Dennis, J. P. Aldinger, C. Jaye, X. Wang, D. A. Fischer, A. N. Cartwright and S. Banerjee, *RSC Adv.*, 2014, **4**, 634–644.

